

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

	PRODUC	1/PKO	CESS CE	IANGE	NOI	ICE (PC	JIN)	
PCN #: TB16	604-01	DATE	22-Apr-2016	MEANS O	F DISTIN	GUISHING (CHANGED I	DEVICES:
Product Affected	: F1912NCGI, F191	2NCGI8		☐ Product ☐ Back M ☐ Date Co ■ Other	lark ode	Traceability to maintained by request		
Date Effective:	22-Jul-2016							
Contact:	IDT PCN DESK			Attachmen	t:	Yes		Vo
E-mail:	pcndesk@idt.com				Please cor sample rec	ntact your loca quest.	l sales repres	entative for
DESCRIPTION	AND PURPOSE OF	CHANGE:						
 □ Die Technolog □ Wafer Fabrica □ Assembly Pro □ Equipment □ Material □ Testing ■ Manufacturing □ Data Sheet □ Other 	Test process follows: t 1 details the c	is to advise our customers that IDT Penang is being added as an alternate process for the selective products that are presently tested at Amkor, tails the change. ts the affected parts.						
RELIABILITY/	QUALIFICATION S	UMMARY:						
There is no expectorrelation data.	ected change to the prod.	duct quality	or reliability per	formance. F	Please refe	r to Attachme	nt 1 for Elect	rical
IDT records indito grant approva it will be assume	CKNOWLEDGMEN' icate that you require well or request additional it and that this change is accertified to ship either version.	ritten notification.	ation of this cha If IDT does not	receive ack	nowledge	ment within 30	days of this	
on the earlier ver	rsion has been depleted	•						
Customer:			_ □] Appro	oval for s	hipments p	rior to effe	ctive date.
Name/Date:			E-	Mail Addre	ess:			
Title:			_ Ph	none# /Fax#	·:			
CUSTOMER C	OMMENTS:							
IDT ACKNOW	LEDGMENT OF REC	CEIPT:						
RECD. BY:				DATE: _				

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ATTACHMENT 1 - PCN # : TB1604-01

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT Penang is being added as an alternate facility for Test process for the selective products that are presently tested at Amkor, Korea facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Tester configuration used at Amkor, Korea is the same as IDT Penang. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.

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ATTACHMENT 1 - PCN #: TB1604-01

Qualification Information and Qualification Data: Electrical Test Correlation Results

Vehicle: F1912NCGI

Sample size: 10 electrically good units and 4 golden units

Description	Golden units/ Lab data	Golden units/ ATE data		
Tester Platform	Bench equipment	J750		
Test Program	N/A	F1912_FT_Rx (where x is program revision)		
Test Site	N/A	4		
Test Temperature	25°C	25°C		
Test Correlation Results	100%	100%		
Number of Golden Units Correlated @ ambient	4 pcs	4 pcs		
4 units of golden units datalog correlation	Correlated	Correlated		
10 units Bin 1 handtest correlation (4 sites)	N/A	Correlated		